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PATENT NUMBER

U.S. UTILITY Patent Application

SCANNED Q.A. A.G.

CONT/PRIOR CLASS SUBCLASS ART UNIT EXAMINER EVENT ANT 1763

2825

PATENT DATE

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Apparatus and method for optical evaluation, apparatus and method for manufacturing semiconductor device, method of controlling apparatus for manufacturing semiconductor device, and semiconductor

PTO-2040 12/99

ISSUING CLASSIFICATION				
ORIGINAL		CROSS REFERENCE(S)		
CLASS SUBCLASS	gLass ,	SUBCLASS (ONE SUBCLASS PER BLOCK)		
1438 /14	#38/	17 9 / /		
INTERNATIONAL CLASSIFICATION	1//			
HO12 /21/166				
		Continued on Issue Slip Inside File Jacket		

TERMINAL DISCLAIMER	PRAWINGS	CLAIMS ALLOWED	
	Sheets Drwg: Figs. Drwg: Print Fig. 39 30 c	Total Claims Print Claim for O.G.	
The term of this patent subsequent to (date)	1	NOTICE OF ALLOWANCE MAILED	
has been disclaimed. The term of this patent shall obtevatend beyond the expiration date of U.S Patent. No. 61395	(Assistant Examiner) (Date)	ISSUE FEE	
	(Primary Examiner) (Date)	Amount Due Date Paid	
The terminalmonths of this patent have been disclaimed.	(Legal Instruments Examiner) (Date)	ISSUE BATCH NUMBER	

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